# IR2155

## SELF-OSCILLATING HALF-BRIDGE DRIVER

#### **Features**

- Floating channel designed for bootstrap operation Fully operational to +600V

  Tolerant to negative transient voltage dV/dt immune
- Undervoltage lockout
- Programmable oscillator frequency

$$f = \frac{1}{1.4 \times (R_{\mathsf{T}} + 150\Omega) \times C_{\mathsf{T}}}$$

- Matched propagation delay for both channels
- Micropower supply startup current of 125 µA typ.
- Low side output in phase with R<sub>T</sub>

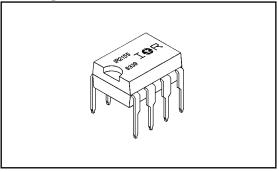
## **Description**

The IR2155 is a high voltage, high speed, self-oscillating power MOSFET and IGBT driver with both high and low side referenced output channels. Proprietary HVIC and latch immune CMOS technologies enable ruggedized monolithic construction. The front end features a programmable oscillator which is similar to the 555 timer. The output drivers feature a high pulse current buffer stage and an internal deadtime designed for minimum driver cross-conduction. Propagation delays for the two channels are matched to simplify use in 50% duty cycle applications. The floating channel can be used to drive an N-channel power MOSFET or IGBT

## **Product Summary**

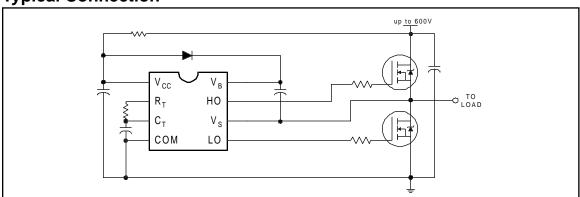
Voffset	600V max.
<b>Duty Cycle</b>	50%
l <sub>O</sub> +/-	210 mA / 420 mA
V <sub>OUT</sub>	10 - 20V
Deadtime (typ.)	1.2 µs

#### **Package**



in the high side configuration that operates off a high voltage rail up to 600 volts.

## **Typical Connection**



#### **Absolute Maximum Ratings**

Absolute Maximum Ratings indicate sustained limits beyond which damage to the device may occur. All voltage parameters are absolute voltages referenced to COM. The Thermal Resistance and Power Dissipation ratings are measured under board mounted and still air conditions

	Parameter		Va	lue	
Symbol	Definition		Min.	Max.	Units
V <sub>B</sub>	High Side Floating Supply Voltage		-0.3	625	
Vs	High Side Floating Supply Offset Voltage		V <sub>B</sub> - 25	V <sub>B</sub> + 0.3	
V <sub>HO</sub>	High Side Floating Output Voltage		V <sub>S</sub> - 0.3	V <sub>B</sub> + 0.3	V
$V_{LO}$	Low Side Output Voltage		-0.3	V <sub>CC</sub> + 0.3	V
V <sub>RT</sub>	R <sub>T</sub> Voltage		-0.3	V <sub>CC</sub> + 0.3	
V <sub>CT</sub>	C <sub>T</sub> Voltage		-0.3	V <sub>CC</sub> + 0.3	
Icc	Supply Current (Note 1)		_	25	mA
I <sub>RT</sub>	R <sub>T</sub> Output Current		-5	5	ША
dV <sub>S</sub> /dt	Allowable Offset Supply Voltage Transient		_	50	V/ns
PD	Package Power Dissipation @ T <sub>A</sub> ≤ +25°C	(8 Lead DIP)	_	1.0	W
		(8 Lead SOIC)	_	0.625	VV
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(8 Lead DIP)	_	125	°C/W
		(8 Lead SOIC)	_	200	C/VV
TJ	Junction Temperature		_	150	
T <sub>S</sub>	Storage Temperature		-55	150	°C
TL	Lead Temperature (Soldering, 10 seconds)		_	300	

## **Recommended Operating Conditions**

The Input/Output logic timing diagram is shown in Figure 1. For proper operation the device should be used within the recommended conditions. The  $V_S$  offset rating is tested with all supplies biased at 15V differential.

	Parameter	Va		
Symbol	Definition	Min.	Max.	Units
V <sub>B</sub>	High Side Floating Supply Absolute Voltage	V <sub>S</sub> + 10	V <sub>S</sub> + 20	
Vs	High Side Floating Supply Offset Voltage	_	600	v
V <sub>HO</sub>	High Side Floating Output Voltage	٧s	V <sub>B</sub>	V
$V_{LO}$	Low Side Output Voltage	0	V <sub>CC</sub>	
Icc	Supply Current (Note 1)		5	mA
T <sub>A</sub>	Ambient Temperature	-40	125	°C

Note 1: Because of the IR2155's application specificity toward off-line supply systems, this IC contains a zener clamp structure between the chip V<sub>CC</sub> and COM which has a nominal breakdown voltage of 15.6V. Therefore, the IC supply voltage is normally derived by forcing current into the supply lead (typically by means of a high value resistor connected between the chip V<sub>CC</sub> and the rectified line voltage and a local decoupling capacitor from V<sub>CC</sub> to COM) and allowing the internal zener clamp circuit to determine the nominal supply voltage. Therefore, this circuit should not be driven by a DC, low impedance power source of greater than V<sub>CLAMP</sub>.

## **Dynamic Electrical Characteristics**

V<sub>BIAS</sub> (V<sub>CC</sub>, V<sub>BS</sub>) = 12V, C<sub>L</sub> = 1000 pF and T<sub>A</sub> = 25°C unless otherwise specified.

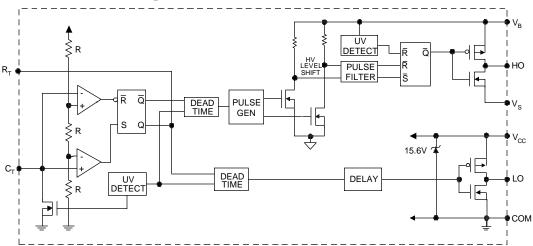
Parameter		Value				
Symbol	Definition	Min.	Тур.	Max.	Units	Test Conditions
t <sub>r</sub>	Turn-On Rise Time	_	80	120	nc	
t <sub>r</sub>	Turn-Off Fall Time	_	40	70	ns	
DT	Deadtime	0.50	1.20	2.25	μs	
D	R <sub>T</sub> Duty Cycle	48	50	52	%	

#### **Static Electrical Characteristics**

 $V_{BIAS}$  ( $V_{CC}$ ,  $V_{BS}$ ) = 12V,  $C_L$  = 1000 pF,  $C_T$  = 1 nF and  $T_A$  = 25°C unless otherwise specified. The  $V_{IN}$ ,  $V_{TH}$  and  $I_{IN}$  parameters are referenced to COM. The  $V_O$  and  $I_O$  parameters are referenced to COM and are applicable to the respective output leads: HO or LO.

Parameter			Value			
Symbol	Definition	Min.	Тур.	Max.	Units	Test Conditions
fosc	Oscillator Frequency	19.4	20.0	20.6	kHz	$R_T = 35.7 \text{ k}\Omega$
		94	100	106	KIIZ	$R_T = 7.04 \text{ k}\Omega$
V <sub>CLAMP</sub>	V <sub>CC</sub> Zener Shunt Clamp Voltage	14.4	15.6	16.8		$I_{CC} = 5 \text{ mA}$
V <sub>CT+</sub>	2/3 V <sub>CC</sub> Threshold	7.8	8.0	8.2	V	
V <sub>CT-</sub>	1/3 V <sub>CC</sub> Threshold	3.8	4.0	4.2		
V <sub>CTUV</sub>	C <sub>T</sub> Undervoltage Lockout	_	20	50		$2.5V < V_{CC} < V_{CCUV}$
V <sub>RT+</sub>	R <sub>T</sub> High Level Output Voltage, V <sub>CC</sub> - R <sub>T</sub>		0	100		I <sub>RT</sub> = -100 μA
		-	200	300		$I_{RT} = -1 \text{ mA}$
$V_{RT ext{-}}$	R <sub>T</sub> Low Level Output Voltage	_	20	50	mV	I <sub>RT</sub> = 100 μA
		_	200	300	1111	I <sub>RT</sub> = 1 mA
$V_{RTUV}$	RT Undervoltage Lockout, V <sub>CC</sub> - R <sub>T</sub>	_	0	100		$2.5V < V_{CC} < V_{CCUV}$
V <sub>OH</sub>	High Level Output Voltage, V <sub>BIAS</sub> - V <sub>O</sub>	_	_	100		I <sub>O</sub> = 0A
V <sub>OL</sub>	Low Level Output Voltage, VO	_	_	100		$I_O = 0A$
I <sub>LK</sub>	Offset Supply Leakage Current		-	50		$V_{B} = V_{S} = 600V$
I <sub>QBS</sub>	Quiescent V <sub>BS</sub> Supply Current	_	70	150		
I <sub>QBSUV</sub>	Micropower V <sub>BS</sub> Supply Startup Current	_	55	125	μA	
I <sub>QCC</sub>	Quiescent V <sub>CC</sub> Supply Current	_	500	1000	μΑ	
I <sub>QCCUV</sub>	Micropower V <sub>CC</sub> Supply Startup Current	_	70	150		
I <sub>CT</sub>	C <sub>T</sub> Input Current	_	0.001	1.0		
V <sub>BSUV+</sub>	V <sub>BS</sub> Supply Undervoltage Positive Going Threshold	7.7	8.4	9.2	V	
V <sub>BSUV</sub> -	V <sub>BS</sub> Supply Undervoltage Negative Going Threshold	7.3	8.1	8.9	v	
V <sub>BSUVH</sub>	V <sub>BS</sub> Supply Undervoltage Lockout Hysteresis	100	400	_	mV	
V <sub>CCUV+</sub>	V <sub>CC</sub> Supply Undervoltage Positive Going Threshold	7.7	8.4	9.2		
V <sub>CCUV</sub> -	V <sub>CC</sub> Supply Undervoltage Negative Going Threshold	7.4	8.1	8.9	V	
V <sub>CCUVH</sub>	V <sub>CC</sub> Supply Undervoltage Lockout Hysteresis	200	400	_	mV	
I <sub>O+</sub>	Output High Short Circuit Pulsed Current	210	250	_	mA	$V_O = 0V$
l <sub>0-</sub>	Output Low Short Circuit Pulsed Current	420	500	_	111/4	V <sub>O</sub> = 15V

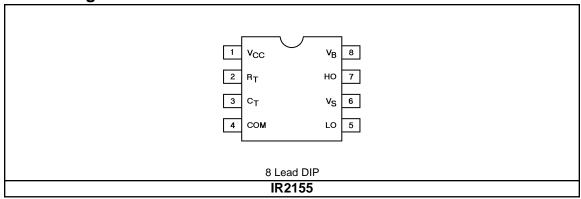
## **Functional Block Diagram**



#### **Lead Definitions**

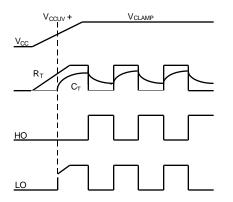
Le	ad					
Symbol	Description					
R <sub>T</sub>	Oscillator timing resistor input,in phase with LO for normal IC operation					
C <sub>T</sub>	Oscillator timing capacitor input, the oscillator frequency according to the following equation:					
	$f = \frac{1}{1.4 \times (R_T + 150\Omega) \times C_T}$					
	where $150\Omega$ is the effective impedance of the R <sub>T</sub> output stage					
V <sub>B</sub>	High side floating supply					
НО	High side gate drive output					
VS	High side floating supply return					
Vcc	Low side and logic fixed supply					
LO	Low side gate drive output					
COM	Low side return					

## **Lead Assignments**



## **Device Information**

Process &	Design Rule		HVDCMOS 4.0 µm		
Transistor Count			260		
Die Size			88 X 92 X 26 (mil)		
Die Outline	Die Outline				
Thickness	of Gate Oxide		800Å		
Connection		Material	Poly Silicon		
	First	Width	4 μm		
	Layer	Spacing	6 μm		
	.,	Thickness	5000Å		
		Material	AI - Si (Si: 1.0% ±0.1%)		
	Second	Width	6 µm		
	Layer	Spacing	9 µm		
	,	Thickness	20,000Å		
Contact Ho	le Dimension		8 µm X 8 µm		
Insulation L		Material	PSG (SiO <sub>2</sub> )		
	,	Thickness	1.5 µm		
Passivation	 	Material	PSG (SiO <sub>2</sub> )		
		Thickness	1.5 µm		
Method of \$	Saw		Full Cut		
Method of I			Ablebond 84 - 1		
Wire Bond		Method	Thermo Sonic		
	Wile Bella		Au (1.0 mil / 1.3 mil)		
Leadframe	Leadframe		Cu		
		Material Die Area	Ag		
		Lead Plating	Pb : Sn (37 : 63)		
Package			8 Lead PDIP / SO-8		
· Sanaga	Materials		EME6300 / MP150 / MP190		
Remarks:			23337, 1337, 100		



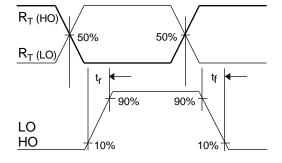


Figure 1. Input/Output Timing Diagram

Figure 2. Switching Time Waveform Definitions

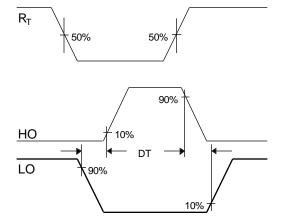


Figure 3. Deadtime Waveform Definitions